

Contents

1	Soft Errors from Space to Ground: Historical Overview, Empirical Evidence, and Future Trends	1
	Tino Heijmen	
2	Single Event Effects: Mechanisms and Classification	27
	Rémi Gaillard	
3	JEDEC Standards on Measurement and Reporting of Alpha Particle and Terrestrial Cosmic Ray Induced Soft Errors	55
	Charles Slayman	
4	Gate Level Modeling and Simulation	77
	Nadine Buard and Lorena Anghel	
5	Circuit and System Level Single-Event Effects Modeling and Simulation	103
	Dan Alexandrescu	
6	Hardware Fault Injection	141
	Luis Entrena, Celia López Ongil, Mario García Valderas, Marta Portela García, and Michael Nicolaidis	
7	Integrated Circuit Qualification for Space and Ground-Level Applications: Accelerated Tests and Error-Rate Predictions	167
	Raoul Velazco, Gilles Foucard, and Paul Peronnard	
8	Circuit-Level Soft-Error Mitigation	203
	Michael Nicolaidis	

9	Software-Level Soft-Error Mitigation Techniques	253
	Maurizio Rebaudengo, Matteo Sonza Reorda, and Massimo Violante	
10	Specification and Verification of Soft Error Performance in Reliable Electronic Systems	287
	Allan L. Silburt, Adrian Evans, Ana Burghilea, Shi-Jie Wen, David Ward, Ron Norrish, Dean Hogle, and Ian Perriman	
	Index	313



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